

<b>PCN Number:</b>	20140306001			<b>PCN Date:</b>	03/13/2014				
<b>Title:</b>	Design Revision (NBTI Fix for Select TPS40077PWP Devices)								
<b>Customer Contact:</b>	<a href="#">PCN Manager</a>	<b>Phone:</b>	+1(214)480-6037	<b>Dept:</b>	Quality Services				
<b>Proposed 1<sup>st</sup> Ship Date:</b>	06/13/2014	<b>Estimated Sample Availability:</b>		Date provided at sample request					
<b>Change Type:</b>									
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials				
<input checked="" type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification				
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process				
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process				
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process				
	<input type="checkbox"/>	Part number change							
<b>PCN Details</b>									
<b>Description of Change:</b>									
<p>This notification is to inform of a design revision for select TPS40077PWP devices. This design change does not affect the device's guaranteed datasheet specifications or electrical performance. The affected devices are listed in the "Product Affected" section.</p> <p>The table below describes changes that were made:</p> <table border="1" style="width: 100%;"> <thead> <tr> <th style="text-align: left;">Description of Change</th> <th style="text-align: left;">Benefit of Change</th> </tr> </thead> <tbody> <tr> <td>Continuous improvement to remove sensitivity over time to negative bias temperature instability (NBTI) under high temperature conditions.</td> <td>Improve reliability</td> </tr> </tbody> </table>						Description of Change	Benefit of Change	Continuous improvement to remove sensitivity over time to negative bias temperature instability (NBTI) under high temperature conditions.	Improve reliability
Description of Change	Benefit of Change								
Continuous improvement to remove sensitivity over time to negative bias temperature instability (NBTI) under high temperature conditions.	Improve reliability								
<b>Reason for Change:</b>									
Improve reliability									
<b>Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):</b>									
None									
<b>Changes to product identification resulting from this PCN:</b>									
None									
<b>Product Affected:</b>									
TPS40077PWP	TPS40077PWPG4	TPS40077PWPR	TPS40077PWPRG4						

## Qualification Data: Approved 2/27/2014

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

### Qual Vehicle 1: TPS40077PWP

#### Package/Die Construction Details

Assembly Site:	TAI	# Pins-Designator, Family:	16-PWP, HTSSOP
Fab Process:	LBC4	Die Revision:	C

Qualification:  Plan  Test Results

Reliability Test	Conditions	Sample Size (PASS/FAIL)
High Temp Operating Life	125C (168, 500, 1000 Hrs)	80/0
Electrical Characterization, side by side	-	Pass
ESD CDM	+/- 250V	3/0
ESD HBM	+/- 1000V	3/0
Latch-up	(per JESD78)	6/0

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or to your local Field Sales Representative.

Location	E-Mail
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>